#200 JAN 2006

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No.

: National Phase Entry of PCT/EP2004/006314

Applicant

: MASSELINK et al

Filed

: January 31, 2006

TC/A.U. Examiner

:

Docket No.

: 3367-101

Customer No.

: 6449

Confirmation No.

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## INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450

Sir:

In compliance with applicants duty of disclosure under 37 C.F.R. 1.56, enclosed is a copy of the International Search Report in the corresponding international application. The relevance of the references is noted in the International Search Report. We understand that the references have been forwarded by the International Bureau, and are available to the Examiner, but if the Examiner needs copies of any of the references, the Examiner is requested to advise counsel accordingly. Also listed on the 1449 are references that are known to the applicant. Also enclosed is an English translation of an office action in the corresponding German priority application and, the cited references are also listed on the attached 1449. A copy of all of the non-US patent references will follow.

In the event that any fees are due with this paper, please charge our Deposit Account No. 02-2135.

Respectfully submitted,

Bv

Robert B. Murray

Attorney for Applicant

Registration No. 22,980

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				Application Number	New Application 31		
INFORMATION DISCLOSURE				Filing Date	January 31, 2006		
STATEMENT BY APPLICANT			N I	First Named Inventor MASSELINK et al			
				Examiner Name			
				Confirmation No.			
Sheet	1	of	4	Attorney Docket Number	3367-101		

	U.S. PATENT DOCUMENTS							
Examiner Initials*	Cite No.1	U.S. Patent D	ocument  Kind Code <sup>2</sup> (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY			
	1.	2002/162995	A1	Horguchi Naoto NMI et al				
	2.	2003/052317	A1	Ohshima Toshio	3/20/03			
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	9.	6,573,527		Sugiyama	6/3/03			
	10.	6,239,449	B1	Simon Fafard	5/29/01			

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code. ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to place a check mark here if English language translation is attached. AB indicates that only an English language abstract is attached.

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STATEME	STATEMENT BY APPLICANT				MASSELINK et al			
				Group Art Unit				
				Examiner Name				
				Confirmation No.				
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FOREIGN PATENT DOCUMENTS										
Examiner Cite		ļ	Foreign Patent Docui		Name of Patentee or Applicant of	Date of Publication of Cited Document				
Initials*	No.1	Office <sup>3</sup> Code	Number⁴	Kind <sup>5</sup> (if known)	Name of Patentee or Applicant of Cited Document	MM-DD-YYYY	L <sub>e</sub>			
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1	INFORMATION DISCLOSURE				January 31, 2006			
STATEMENT BY APPLICANT			VI	First Named Inventor MASSELINK et al				
				Examiner Name				
				Confirmation No.				
Sheet	3	of	4	Attorney Docket Number	3367-101			

		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T <sup>2</sup>
	12.	Mikhailov SA., "A New Type of Tunable Solid-State Far-Infared Lasers", CONF LASERS ELECTRO OPT EUR TECH DIG, 14 September 1998, pg. 92	
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	14.	Asahi H., "Self-Organized Quantum Wires and Dots in III-V Semiconductors", ADVANCED MATERIALS, vol. 9, no. 13, 3 November 1997, pgs. 1019-1026.	
	15.	Belydev et al., "Positively charged defects associated with self-assembled quantum dot formation", APPLIED PHYSICS LETTERS, vol.76, no. 24, 12 June 2000, pgs. 3570-3572.	
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	17.	F. Capasso et al. "Quantum Kaskade Laser: "Ultrahigh-Speed Operation, Optical Wireless Communication, Narrow Linewidth, and Far-Infrared Emission", IEEED Journal of Quantum Electronics 38, 511 -532, 2002.	
	18.	J. Phillips et al. "Far-Infrared Photoconductivity in self-organized InAs Quantum Dots ", Applied Physics Letters 72, 2020-2022, 1998.	
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					Confirmation No.						
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	26.		H. Asahi, Adv	anced N	Materials 9 (	1997), 1019					
	27.		C. Sirtori, et a	ıl., Appli	ed Physics I	Letters 61, 898					
	28.		Chung et al., "Coupled strained-layer InGaAs quantum well improvement of an InAs quantum dot", APPLIED PHYSICS LETTERS, vol. 79, no. 27, 2001, pgs. 4500-4502.								
Examiner							Date				
Signature			Considered								

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